


<b>Search Notes</b>  	<b>Application/Control No.</b>  09652862	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Ewart, James D	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	12.1, 13.1, 427, 429, 456, 458, 562	03-14-2007	JDE
342	357.01, 357.16, 457		
244	158R		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
same as above		3-14-2007	JDE